TOSHIBA Intelligent Power Device Silicon Monolithic Power MOS Integrated Circuit

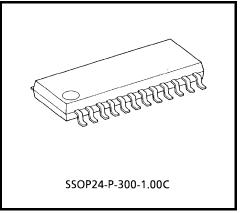
# **TPD7210F**

### Power MOSFET Gate Driver for 3-Phase DC Motor

The TPD7210F is a power MOSFET gate driver for 3-phase full-bridge circuits that use a charge pump system. The inclusion of a charge pump circuit for high-side drive inside the IC makes it easy to configure a 3-phase full-bridge circuit.

### **Features**

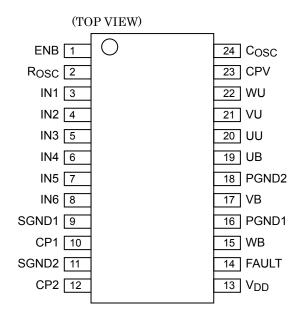
- Power MOSFET gate driver for 3-phase DC motor
- Built-in diagnosis function: under-voltage detection
- Built-in charge pump circuit
- Package: SSOP-24 (300 mil) with embossed-tape packing

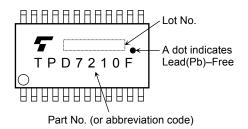


Weight: 0.29 g (typ.)

### **Pin Assignment**

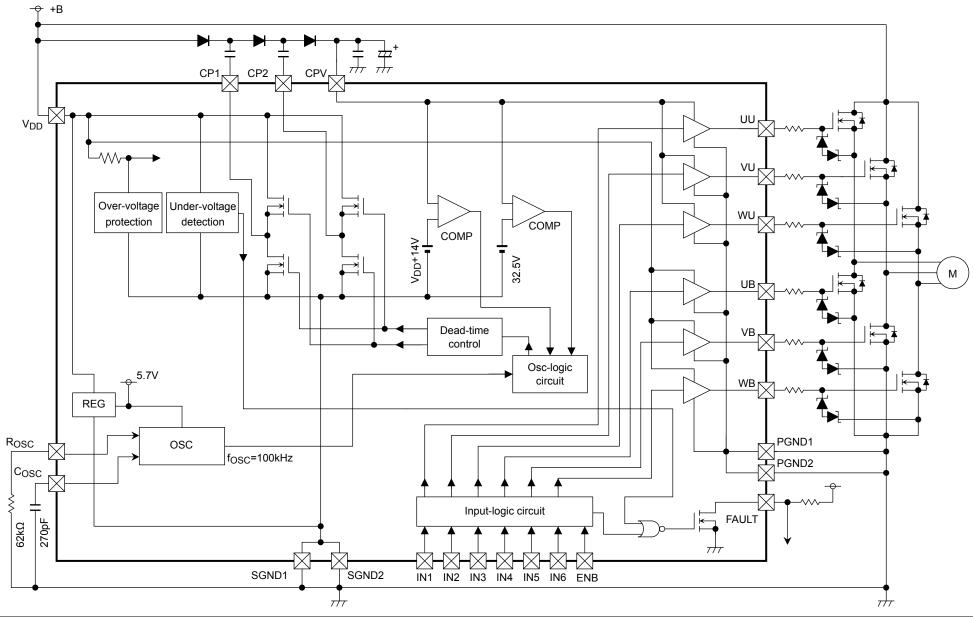
### Marking





This product has a MOS structure and is sensitive to electrostatic discharge.

# **Block Diagram / Application Circuit**



# **Pin Description**

Pin No.	Symbol	Pin Description
1	ENB	Inhibit pin (high active ): By driving this pin low, all outputs can be turned off regardless of input signals. Built-in pull-down resistor (100 k $\Omega$ typ.).
2	Rosc	This pin sets the oscillation frequency for the charge pump drive. Connect a 62 k $\Omega$ (typ.) resistor.
3	IN1	Input pin: it controls the power MOSFET connected to UU. Built-in pull-down resistor (100 k $\Omega$ typ.).
4	IN2	Input pin: it controls the power MOSFET connected to VU. Built-in pull-down resistor (100 k $\Omega$ typ.).
5	IN3	Input pin: it controls the power MOSFET connected to WU. Built-in pull-down resistor (100 k $\Omega$ typ.).
6	IN4	Input pin: it controls the power MOSFET connected to UB. Built-in pull-down resistor (100 k $\Omega$ typ.).
7	IN5	Input pin: it controls the power MOSFET connected to VB. Built-in pull-down resistor (100 k $\Omega$ typ.).
8	IN6	Input pin: it controls the power MOSFET connected to WB. Built-in pull-down resistor (100 k $\Omega$ typ.).
9	SGND1	Signal block GND pin: shared internally with pin 11.
10	CP1	Capacitor pin for charge pump.
11	SGND2	Signal block GND pin: shared internally with pin 9.
12	CP2	Capacitor pin for charge pump.
13	V <sub>DD</sub>	Power supply pin: when under-voltage (5.5 V typ.) is detected, FAULT output goes high. On this occasion, all outputs are switching normally, and charge pump circuit does not come to a stop.
14	FAULT	Diagnosis output pin: when under-voltage (5.5 V typ.) is detected, FAULT output goes high. High-side/low-side arm shorting mode, FAULT output goes high and all outputs are shut down. Circuit configuration is N-ch open drain.
15	WB	Drives the power MOSFET connected to the low side of the W phase.
16	PGND1	Power block GND pin: shared internally with pin 18.
17	VB	Drives the power MOSFET connected to the low side of the V phase.
18	PGND2	Power block GND pin: shared internally with pin 16.
19	UB	Drives the power MOSFET connected to the low side of the U phase.
20	UU	Drives the power MOSFET connected to the high side of the U phase.
21	VU	Drives the power MOSFET connected to the high side of the V phase.
22	WU	Drives the power MOSFET connected to the high side of the W phase.
23	CPV	Final stage capacitor pin for the charge pump.
24	C <sub>OSC</sub>	This pin sets the oscillation frequency for the charge pump drive. Connect a 270pF (typ.) capacitor.

Truth Table (All outputs go to low for input in high-side/low-side arm shorting mode)

Mode				Output									
No.	IN1 (UU)	IN2 (VU)	IN3 (WU)	IN4 (UB)	IN5 (VB)	IN6 (WB)	OUT	OUT VU	OUT WU	OUT UB	OUT VB	OUT WB	Remarks
01	L	L	L	L	L	L	L	L	L	L	L	L	
02	Н	L	L	L	L	L	Н	L	L	L	L	L	
03	L	Η	L	Ш	L	L	L	Ι	L	L	L	L	
04	L	L	Н	Ш	L	L	L	Ш	Н	L	L	L	
05	L	L	L	Ι	L	L	L	Ш	L	Н	L	L	
06	L	L	L	Ш	Н	L	L	Ш	L	L	Η	L	
07	L	L	L	L	L	Н	L	L	L	L	L	Н	
08	Н	L	L	Н	L	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *
09	Н	L	L	L	Н	L	Н	L	L	L	Н	L	120° square wave conducting normal mode
10	Н	L	L	L	L	Н	Н	L	L	L	L	Н	120° square wave conducting normal mode
11	L	Н	L	Н	L	L	L	Н	L	Н	L	L	120° square wave conducting normal mode
12	L	Н	L	L	Н	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *
13	L	Н	L	L	L	Н	L	Н	L	L	L	Н	120° square wave conducting normal mode
14	L	L	Н	Н	L	L	L	L	Н	Н	L	L	120° square wave conducting normal mode
15	L	L	Н	L	Н	L	L	L	Н	L	Н	L	120° square wave conducting normal mode
16	L	L	Н	L	L	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *
17	Н	Н	L	L	L	L	Н	Н	L	L	L	L	
18	L	Н	Н	L	L	L	L	Н	Н	L	L	L	
19	Н	L	Н	L	L	L	Н	L	Н	L	L	L	
20	L	L	L	Н	Н	L	L	L	L	Н	Н	L	
21	L	L	L	L	Н	Н	L	L	L	L	Н	Н	
22	L	L	L	Н	L	Н	L	L	L	Н	L	Н	
23	Н	Н	L	Н	L	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *
24	Н	Н	L	L	Н	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *
25	Н	Н	L	L	L	Н	Η	Н	L	L	L	Н	
26	L	Н	Н	Н	L	L	L	Н	Н	Н	L	L	
27	L	Н	Н	L	Н	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *
28	L	Н	Н	L	L	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *
29	Н	L	Н	Н	L	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *
30	Н	L	Н	L	Н	L	Н	L	Н	L	Н	L	

<sup>\*:</sup> High-side/low-side arm shorting mode is disabled by the internal logic. FAULT output goes high (open-drain, high-impedance)

<sup>\*:</sup> By driving ENB pin low, all outputs can be turned off regardless of input signals. By driving ENB pin high, all outputs are switching normally.

Mode			Inp	out			Output							
No.	IN1 (UU)	IN2 (VU)	IN3 (WU)	IN4 (UB)	IN5 (VB)	IN6 (WB)	OUT	OUT VU	OUT WU	OUT UB	OUT VB	OUT WB	Remarks	
31	Н	L	Н	L	L	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
32	Н	L	L	Н	Η	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
33	Н	L	L	L	Н	Н	Н	L	L	L	Н	Н		
34	Н	L	L	Н	L	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
35	L	Н	L	Н	Н	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
36	L	Н	L	L	Н	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
37	L	Н	٦	Н	L	Н	L	Н	L	Н	L	Н		
38	L	L	Η	Н	Н	L	L	L	Н	Н	Н	L		
39	L	L	Н	L	Ι	Η	Ш	L	L	L	L	L	High-side/low-side arm shorting mode *	
40	L	L	Н	Η	L	Η	Ш	L	L	L	L	L	High-side/low-side arm shorting mode *	
41	Н	Н	Н	L	L	L	Ι	Н	Н	L	L	L		
42	L	L	L	Η	Ι	Η	Ш	L	L	Н	Н	Н		
43	Н	Н	L	Η	Ι	L	Ш	L	L	L	L	L	High-side/low-side arm shorting mode *	
44	Н	Н	L	L	Ι	Η	Ш	L	L	L	L	L	High-side/low-side arm shorting mode *	
45	Н	Н	L	Η	L	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
46	L	Н	Н	Η	Η	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
47	L	Н	Н	L	Η	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
48	L	Н	Н	Η	L	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
49	Н	L	Н	Η	Η	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
50	Н	L	Н	L	Η	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
51	Н	L	Н	Η	L	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
52	Н	Н	Н	Н	L	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
53	Н	Н	Н	L	Η	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
54	Н	Н	Н	L	L	Η	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
55	Н	L	L	Η	Η	Η	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
56	L	Н	L	Η	Η	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
57	L	L	Н	Η	Η	Η	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
58	Н	Н	Н	Н	Н	L	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
59	Н	Н	Н	L	Н	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
60	Н	Н	Н	Н	L	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
61	Н	Н	L	Н	Н	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
62	L	Н	Н	Н	Н	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
63	Н	L	Н	Н	Н	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	
64	Н	Н	Н	Н	Н	Н	L	L	L	L	L	L	High-side/low-side arm shorting mode *	

<sup>\*:</sup> High-side/low-side arm shorting mode is disabled by the internal logic. FAULT output goes high (open-drain, high-impedance)

<sup>\*:</sup> By driving ENB pin low, all outputs can be turned off regardless of input signals. By driving ENB pin high, all outputs are switching normally.

# Absolute Maximum Ratings $(T_a = 25^{\circ}C)$

Characteristic	Symbol	Rating	Unit	Remarks		
Power supply voltage	V <sub>DD(1)</sub>	-0.5 to 30	V			
Power supply voltage	V <sub>DD(2)</sub>	45	V	Pulse width ≤ 200ms		
Output current	ISOURCE	1	Α	Pulso width < 10 us		
Output current	ISINK	1	^	Pulse width ≤ 10μs		
Input voltage	V <sub>IN</sub> , V <sub>ENB</sub>	-0.5 to 7.0	V			
FAULT pin voltage	VFAULT	30	V			
PGND pin negative voltage	P <sub>GND</sub> (-)	-0.5	V	Negative voltage that can be applied to PGND pin (reference to SGND pin)		
Output pin negative voltage	V <sub>OUT(-)</sub>	-0.5	٧	Negative voltage that can be applied to UU, VU,WU,UB,VB and WB pins (Reference to SGND pin)		
FAULT pin current	IFAULT	5	mA			
Dowar dissination	D-	0.8	w			
Power dissipation	P <sub>D</sub>	1.2 (Note2)	VV			
Operating temperature	T <sub>opr</sub>	-40 to 125	°C			
Junction temperature	Tj	150	°C			
Storage temperature	T <sub>stg</sub>	-40 to 150	°C			

Note1: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### **Thermal Resistance**

Characteristic	Symbol	Rating	Unit
Junction to ambient thermal resistance	Du (1)	156.3	°C/W
Junction to ambient thermal resistance	R <sub>th (j-a)</sub>	104.2 (Note2)	C / VV

Note2: When the device is mounted on a 60 mm  $\times$  60 mm  $\times$  1.6 mm glass epoxy PCB

Electrical Characteristics (Unless otherwise specified,  $T_a$  = -40 to 125°C, CP1, 2 = 0.1 $\mu$ F,  $R_{OSC}$  = 62 $k\Omega$ ,  $C_{OSC}$  = 270pF)

Characteristic	Symbol	Test Circuit	Condition	Min	Тур.	Max	Unit	Remarks	
Operating supply voltage (Note3)	V <sub>DD(opr)</sub>	-	-	4.5	13.5	18	V		
	I <sub>DD(1)</sub>	-	V <sub>DD</sub> = 13.5 V	-	-	7		Oscillation circuit stops	
Supply current			V <sub>DD</sub> = 13.5 V, V <sub>IN1</sub> to V <sub>IN6</sub> = 0 V, CP1,2 = 0.1μF	-	ı	9	mA	When oscillation circuit is operating f = 100 kHz, mean current	
Input voltage	V <sub>IH</sub>		V <sub>DD</sub> = 7 to 18 V,	3.5	ı	_	V	IN1 to IN6 and ENB High-level input voltage	
input voltage	V <sub>IL</sub>		I <sub>O</sub> = 0 A	-	ı	1.5	V	IIN1 to IN6 and ENB low-level input voltage	
Input current	I <sub>IH</sub>	_	V <sub>DD</sub> = 7 to 18V, V <sub>IN</sub> = 5 V	-	-	200	μА	IN1 to IN6, ENB input	
input current	I <sub>IL</sub>		V <sub>DD</sub> = 7 to 18 V, V <sub>IN</sub> = 0 V	- 10	ı	10	μА	(per one input)	
Charge pump voltage			V <sub>DD</sub> = 7 V, V <sub>IN1</sub> to V <sub>IN6</sub> = 0 V	V <sub>DD</sub> +10.9	V <sub>DD</sub> +11.9	-	V	$V_{CPV} \approx 3 \times (V_{DD} - V_F)$ $V_{CPV}$ denotes CPV pin voltage. (reference to SGND pin)	
(Note4)(Note5)	V <sub>CPV</sub>	-	- V <sub>DD</sub> = 13.5 V, V <sub>DD</sub> V <sub>DD</sub> V <sub>DD</sub> V <sub>DD</sub> V <sub>CPV</sub> de voltage.		V <sub>CPV</sub> denotes CPV pin voltage.				
			V <sub>DD</sub> = 18 V, V <sub>IN1</sub> to V <sub>IN6</sub> = 0 V	V <sub>DD</sub> +12	V <sub>DD</sub> +14	V <sub>DD</sub> +16	V	(reference to SGND pin)	
	V <sub>OH(H1)</sub>		V <sub>DD</sub> = 7V, V <sub>IN</sub> = 5V, I <sub>O</sub> = -10mA	-	V <sub>DD</sub> + 9.9	-			
High-side high-level output voltage	V <sub>OH(H2)</sub>	_	V <sub>DD</sub> = 13.5 V, V <sub>IN</sub> = 5 V, I <sub>O</sub> = -10 mA	-	V <sub>DD</sub> + 12	-		UU, VU and WU pin voltage (reference to SGND pin) *Measuring single pulse	
	V <sub>OH(H3)</sub>		V <sub>DD</sub> = 18 V, V <sub>IN</sub> = 5 V, I <sub>O</sub> = -10 mA	1	V <sub>DD</sub> + 12	-			
High-side high-level output voltage drop	V <sub>DROP</sub>		V <sub>IN</sub> = 5 V, I <sub>O</sub> = -10 mA, V <sub>DROP</sub> = V <sub>CPV</sub> - V <sub>OH</sub>	-	2	3	V		
High-side low-level output voltage	V <sub>OL(H)</sub>	-	V <sub>DD</sub> = 7 to 18 V, V <sub>IN</sub> = 0 V, I <sub>O</sub> = 0 A	-	-	0.1			
Low-side high-level output voltage	V <sub>OH(L)</sub>	-	$V_{DD} = 7 \text{ to } 18V,$ $V_{IN} = 5V,$ $I_{O} = -10\text{mA}$	V <sub>DD</sub> - 0.1	V <sub>DD</sub>	-		UB, VB and WB pin voltage	
Low-side low-level output voltage	side low-level V <sub>OL(L)</sub> - V <sub>IN</sub>		V <sub>DD</sub> = 7 to 18 V, V <sub>IN</sub> = 0 V, I <sub>O</sub> = 0 A	-	-	0.1		(reference to SGND pin)	
Output ON registance	R <sub>SOURCE</sub>		$V_{DD} = 13.5 \text{ V},$ $V_{IN} = 5 \text{ V},$ $I_{O} = -0.5 \text{ A}$		7	10	Ω	UU, VU, WU, UB, VB and	
Output ON resistance	R <sub>SINK</sub>	_	V <sub>DD</sub> = 13.5 V, V <sub>IN</sub> = 0 V, I <sub>O</sub> = 0.5 A	-	4.5	10	72	WB output resistance pulse width $\leq$ 10 $\mu$ s	

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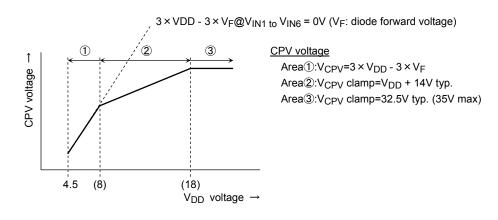
Characteristic		Symbol	Test Circuit	Condition	Min	Тур.	Max	Unit	Remarks	
Under-	Detection	$V_{DDUV}$			5.0	5.5	6.0	V	Under voltage detection	
voltage detection	Hysteresis	$\Delta V_{DDUV}$	_	_	-	0.5	-	V	voltage and hysteresis (V <sub>DD</sub> voltage detected)	
	Turn-on delay time	t <sub>d</sub> (ON)		$V_{DD}$ = 13.5 V, $V_{CPV}$ = 13.5 V, $C_{OUT}$ = 12400 pF, $R_{G}$ = 47 $\Omega$	ı	0.25	1			
Switching	Turn-on time	t <sub>ON</sub>	1		ı	0.5	2	μS	UU, VU, WU, UB, VB and WB switching times	
times	Turn-off delay time	<sup>t</sup> d (OFF)	1		-	0.25	1	μδ		
	Turn-off time	tOFF			ı	0.5	2			
Dead time (Note 6)		<sup>t</sup> dead	-	$V_{DD}$ = 13.5 V, $t_{dead}$ = $t_{OFF}$ - $t_{d(ON)}$	I	0.25	1	μ\$		
Oscillating frequency		fosc -		$V_{DD}$ = 7 to 18V, $R_{OSC}$ = 62 k $\Omega$ , $C_{OSC}$ = 270 pF	80	100	120	kHz		
FAULT output voltage		VFAULT	-	V <sub>DD</sub> = 7 to 18 V, I <sub>FAULT</sub> = 1 mA	I	-	0.8	>	FAULT pin low-level voltage (open-drain)	
FAULT output leakage current		I <sub>FAULT</sub>	_	V <sub>DD</sub> = 7 to 18 V, V <sub>FAULT</sub> = 18 V	_	_	10	μΑ		
FAULT out delay time	put	t <sub>d(FAULT)</sub>	-	-	-	-	1	μS		

Note3 : On-off output control, FAULT output and charge pump circuit operate from  $V_{DD} \ge 4.5V$ . However, charge pump voltage (CPV voltage) decreases by there are a lot of output currents in the condition with a low power supply voltage ( $V_{DD}$ ). It may be not enough voltage ( $V_{GS}$ ) to drive external power MOSFET. Be careful enough when using it .

Note4 : When converting foward voltage of the charge pump circuit diode by 0.7V. Please use the diode of high-speed type ( $trr \le 100ns$ ).

### Note5: About the charge pump voltage

So as not to apply over-voltage to the gate-source voltage ( $V_{GS}$ ) of external power MOSFET, and so as to become the best driving voltage, the clamping circuit is built into. When the CPV voltage reaches the value, so as not to apply over-voltage, the oscillation logic circuit of the charge pump is stopped.





Note6: About the dead time

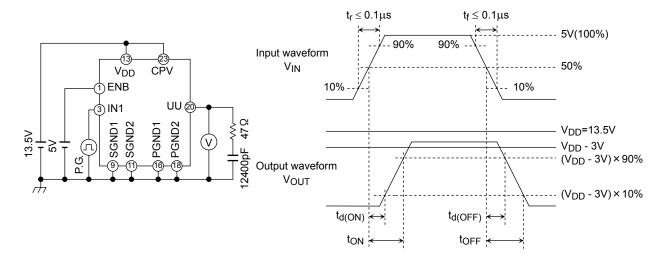
High-side/low-side arm shorting mode is disabled by the internal logic. All outputs can be turned off. The deadtime of this product is  $1\mu s$ . That doesn't contain deadtime of external power MOSFET. Please set the deadtime of the input signal after considering the switching time of external power MOSFET.

Note7 : About the direct input method of the charge pump oscillation frequency By the oscillation signal from the outside to  $C_{OSC}$  it is possible to set up the charge pump oscillation. As this method, please input the signal to  $C_{OSC}$  after  $V_{DD}$  becomes over 9V. ( $V_{COSC} \le 5.5V$ ) Moreover, please use the terminal  $R_{OSC}$  by the resistance unconnection (open). When the CPV voltage reaches up to the clamping voltage, though the signal is input to  $C_{OSC}$ , the movement of the charge pump (oscillation) stops.

### **Test Circuit 1**

### **Switching times**

Example of measuring UU output



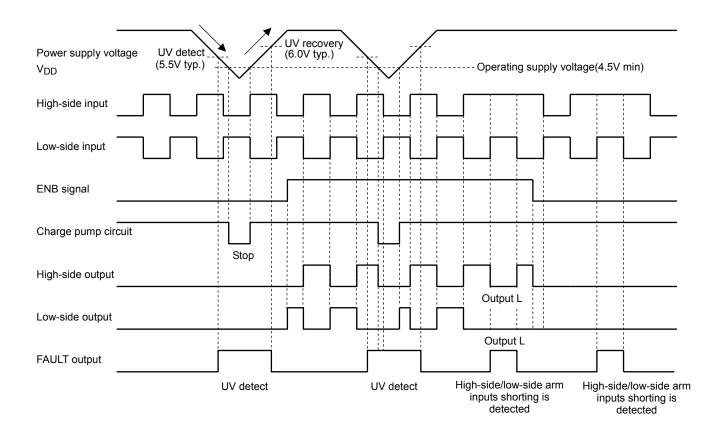
### **Truth Table**

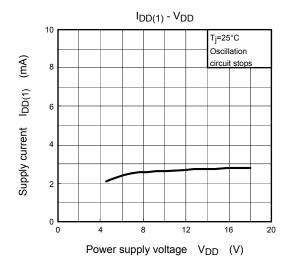
IN	ENB	VOUT	FAULT	STATE
L	L	L	L	
Н	┙	┙	┙	Normal
L	Н	L	L	Normal
Н	Н	Н	L	
L	┙	┙	Η	
Н	┙	┙	Н	V under veltage detection
L	Н	L	Н	V <sub>DD</sub> under-voltage detection
Н	Н	Н	Н	
High-side H	┙	┙	Н	Upper and lower short sirewit input detection
Low-side H	Н	L	Н	Upper and lower short-circuit input detection

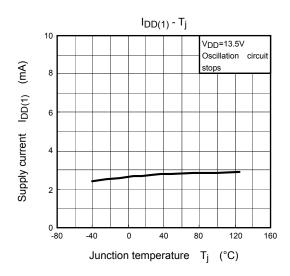
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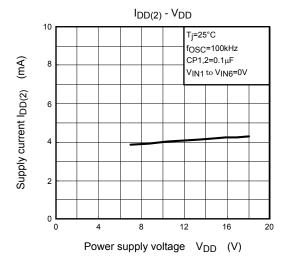
- When under-voltage (5.5V typ.) is detected, only FAULT outputs "H". Neither the output nor the operation of the charge pump circuit stops(off).
- When a in-phase high side and the low side input are the "H" levels, all the outputs be made "L" level, and the "H" level is output to FAULT.

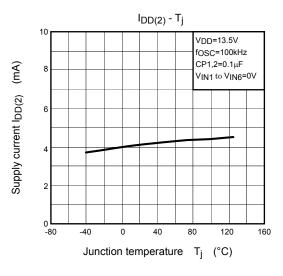
# **Timing chart**

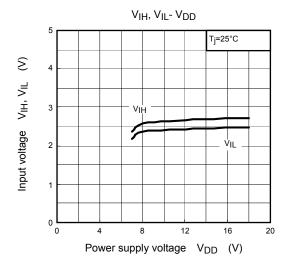


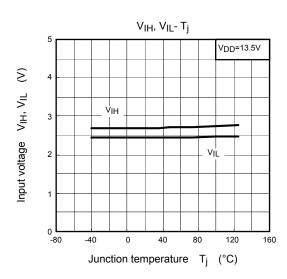




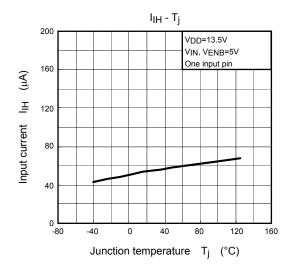


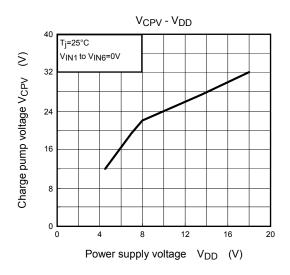


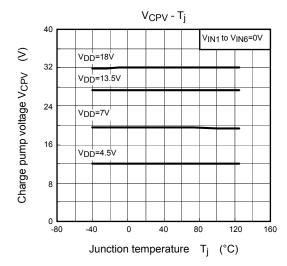


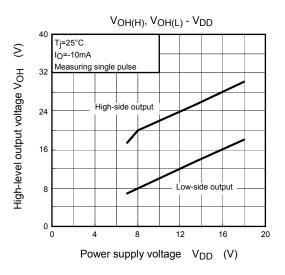


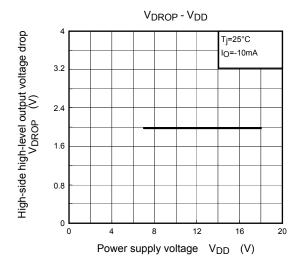
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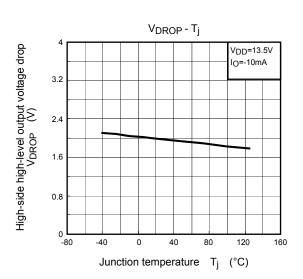




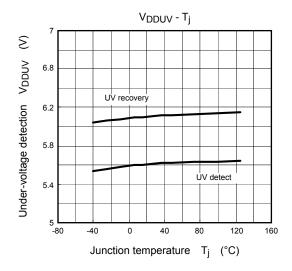


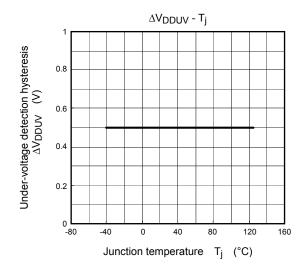


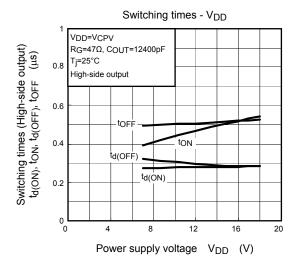


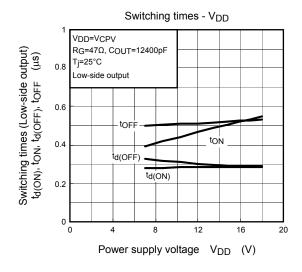


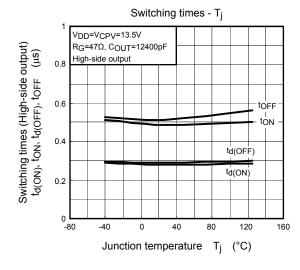
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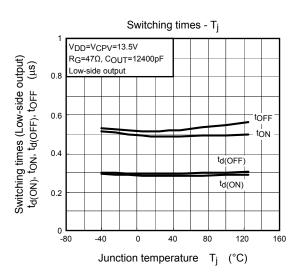


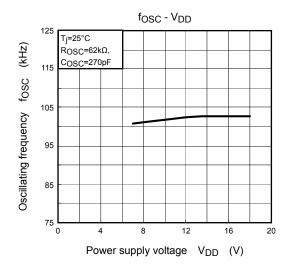


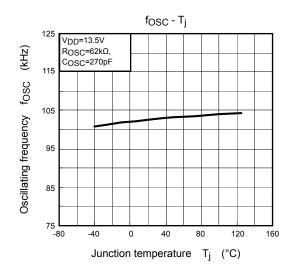


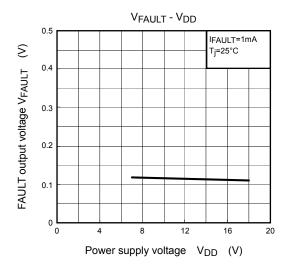


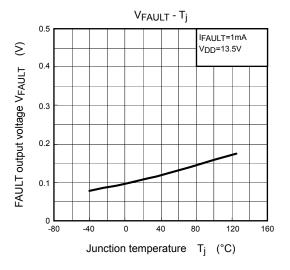


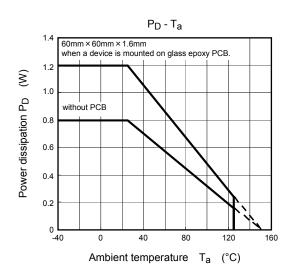










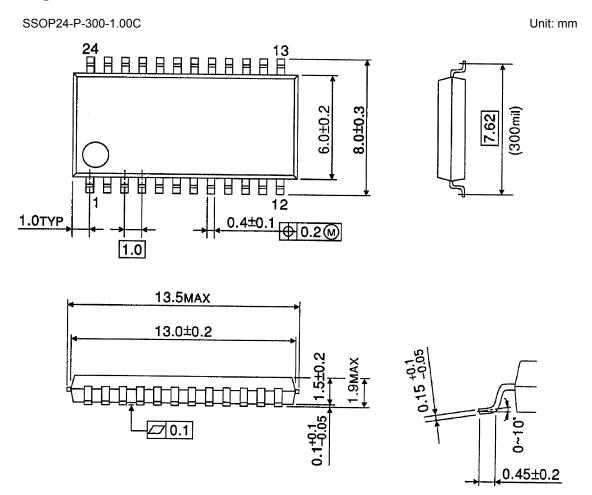


# **Usage Precautions**

Precautions on dry packing

After unpacking dry or moisture-proof packing, make sure the device is mounted in place within 48 hours at a temperature and humidity of 30°C and 60% RH or less. Because the device is emboss-taped and cannot be processed by baking, always be sure to use it within the said allowable time after unpacking. Standard tape packing quantity: 2000 devices / reel (EL1).

# **Package Dimensions**



Weight: 0.29 g (typ.)

### RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
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